On the Total Variation Distance of SMCs

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FOCUS seminars

Before to start...

Given $\mu, \nu: \Sigma \to \mathbb{R}_+$ measures on (X, Σ)

Total Variation Distance -

$$||\mu - \nu|| = \sup_{E \in \Sigma} |\mu(E) - \nu(E)|$$

Before to start...

Given $\mu, \nu: \Sigma \to \mathbb{R}_+$ measures on (X, Σ)

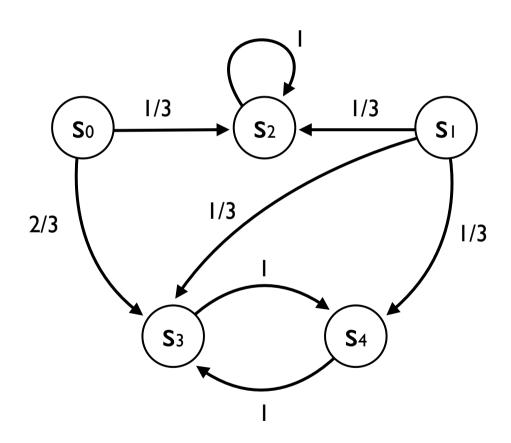
Total Variation Distance

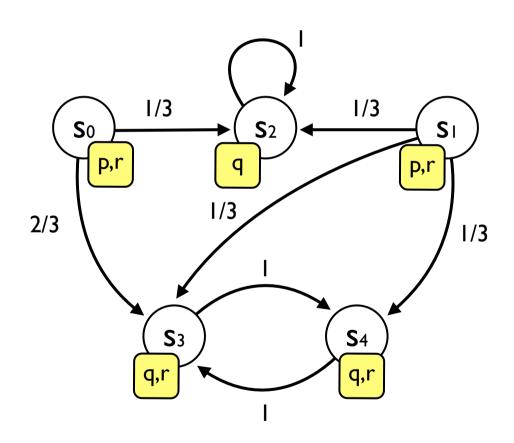
$$\|\mu - \nu\| = \sup_{E \in \Sigma} |\mu(E) - \nu(E)|$$

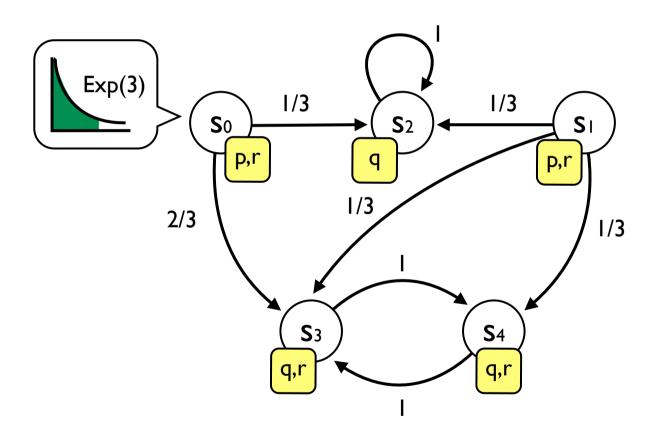
The largest possible difference that µ and V assign to the same event

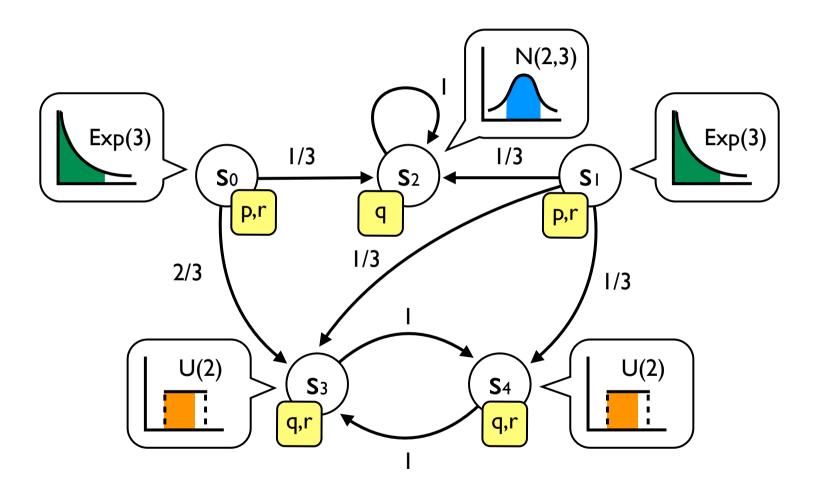
Outline

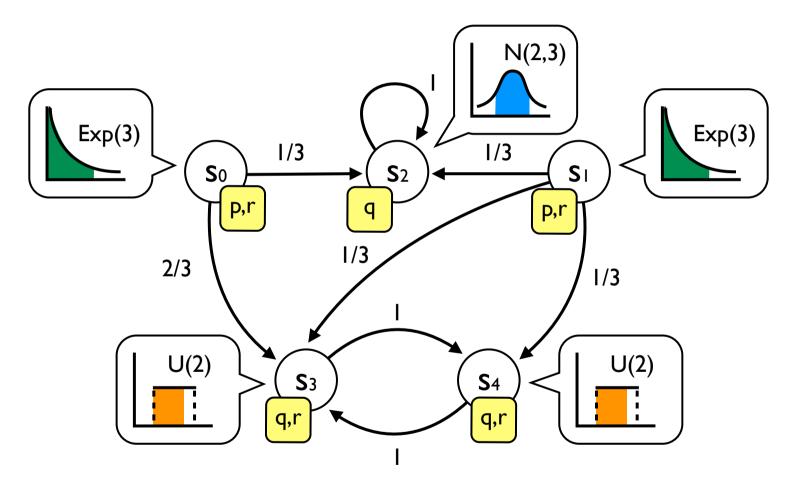
- Semi-Markov Chains (SMCs)
- Total Variation vs Model Checking of SMCs
- An Approximation Algorithm
- Concluding Remarks











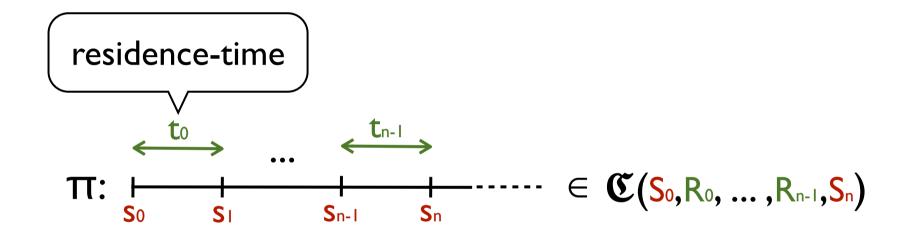
Given an initial state, SMCs can be interpreted as "machines" that emit timed traces of states with a certain probability

Timed paths & Events

$$\pi : \xrightarrow{\mathsf{t}_0} \dots \xrightarrow{\mathsf{t}_{n-1}} \dots \in \mathfrak{C}(\mathsf{S}_0,\mathsf{R}_0,\dots,\mathsf{R}_{n-1},\mathsf{S}_n)$$

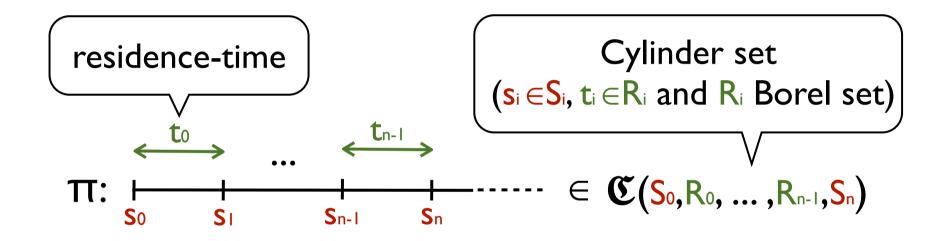
"probability that, starting from s,
$$P[s](\mathfrak{C}(S_0,R_0,...,R_{n-1},S_n)) =$$
 the SMC emits a timed path with prefix in $S_0 \times R_0 \times ... \times R_{n-1} \times S_n$ "

Timed paths & Events

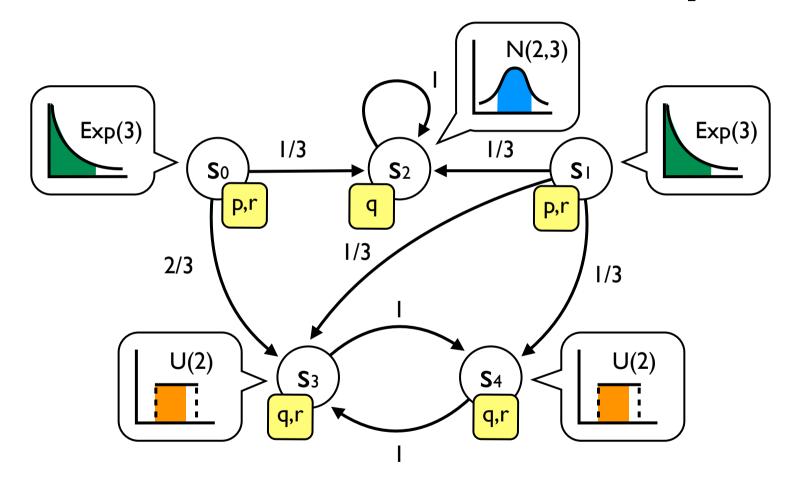


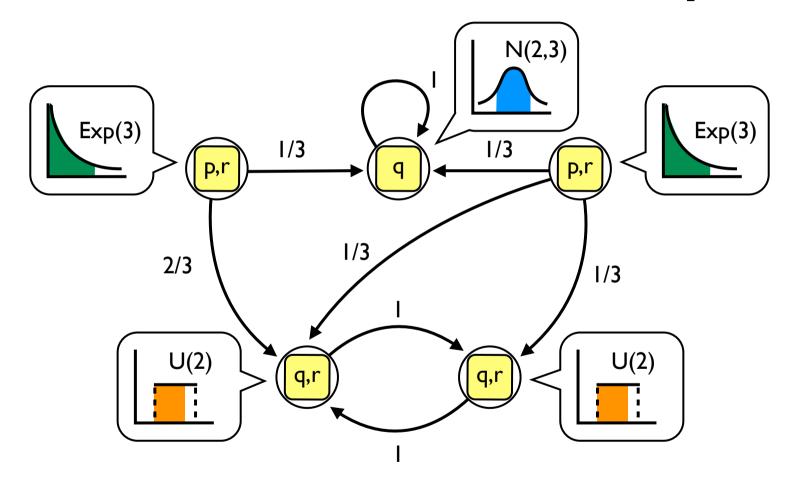
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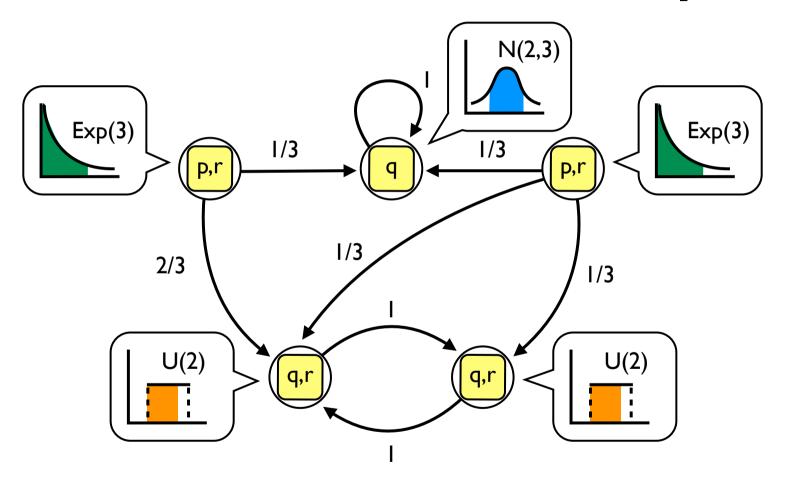
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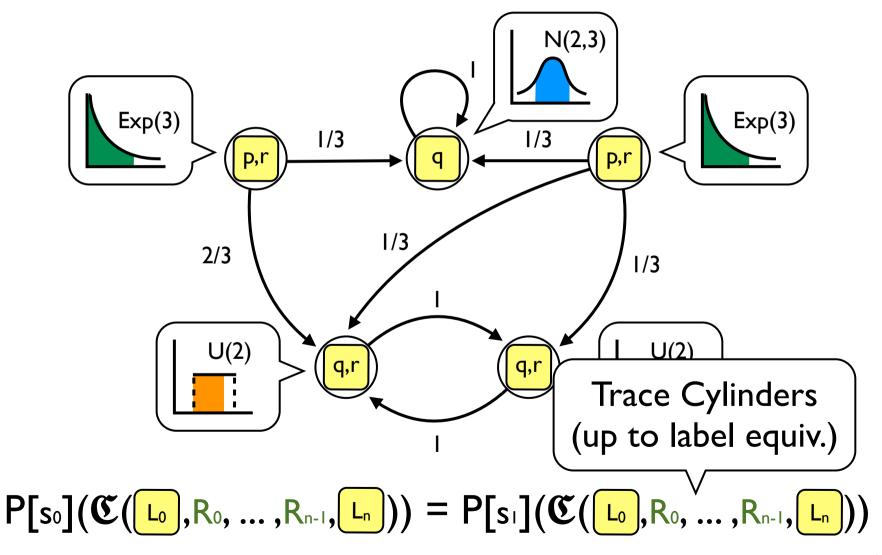
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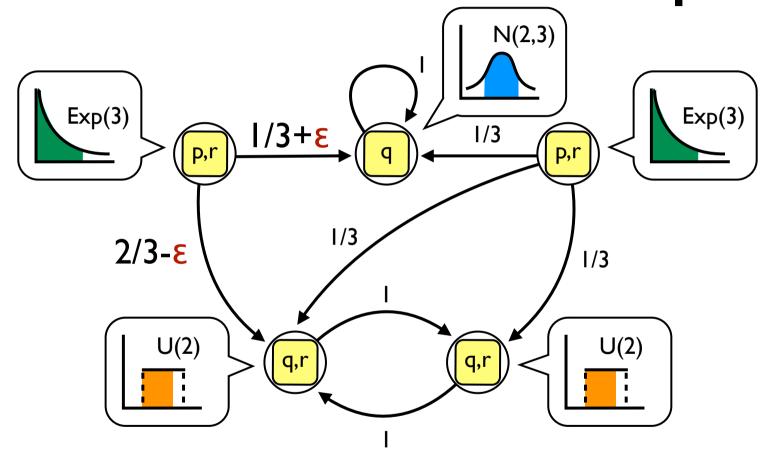




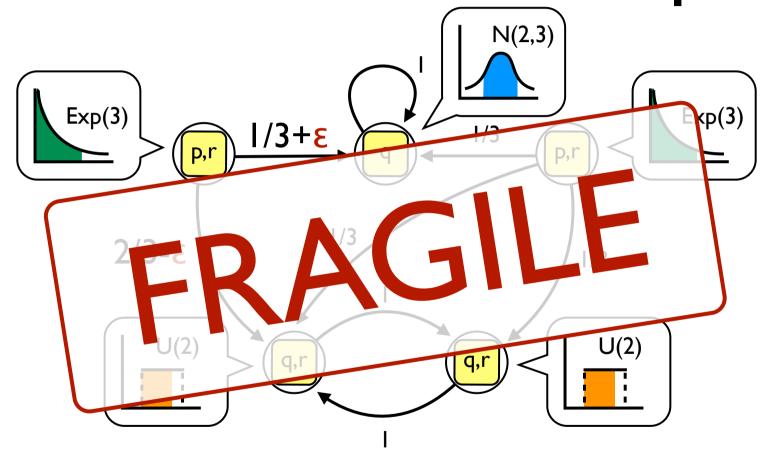


$$P[s_0](\mathfrak{C}(L_0,R_0,\ldots,R_{n-1},L_n))=P[s_1](\mathfrak{C}(L_0,R_0,\ldots,R_{n-1},L_n))$$





$$P[s_0](\mathfrak{C}(P,r),\mathbb{R},\mathbb{Q},)) = 1/3 + \varepsilon \neq 1/3 = P[s_1](\mathfrak{C}(P,r),\mathbb{R},\mathbb{Q},))$$



$$P[s_0](\mathfrak{C}([p,r],\mathbb{R},[q],)) = 1/3 + \varepsilon \neq 1/3 = P[s_1](\mathfrak{C}([p,r],\mathbb{R},[q],))$$

Trace Pseudometric

$$d(s,s') = \sup_{E \in \sigma(\mathcal{T})} |P[s](E) - P[s'](E)|$$

$$\sigma\text{-algebra generated from Trace Cylinders}$$

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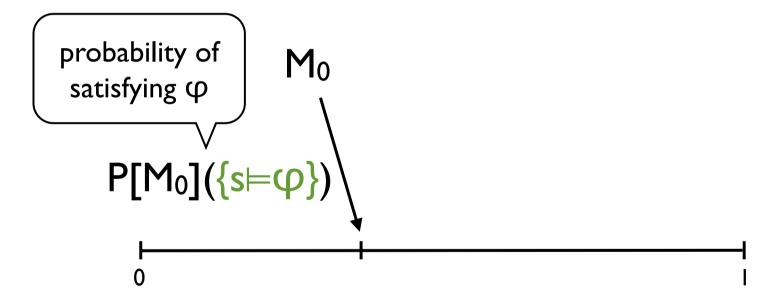
It's a Behavioral Distance! —

$$d(s,s') = 0$$
 iff $s \approx_T s'$

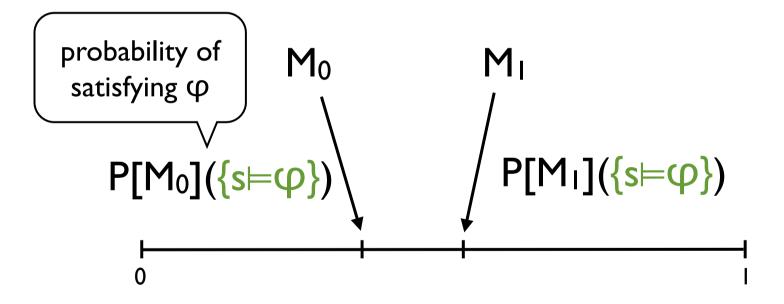
Distance = Approx. Error

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Distance Approx. Error

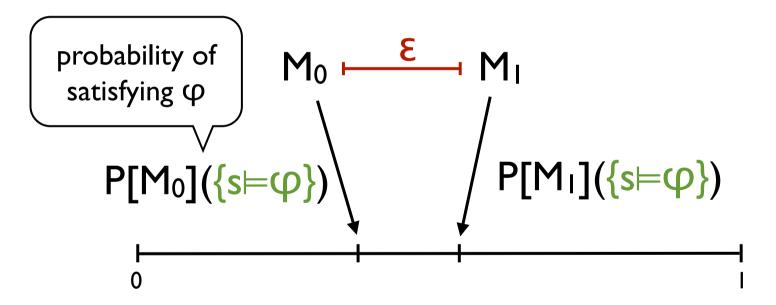


Distance Approx. Error



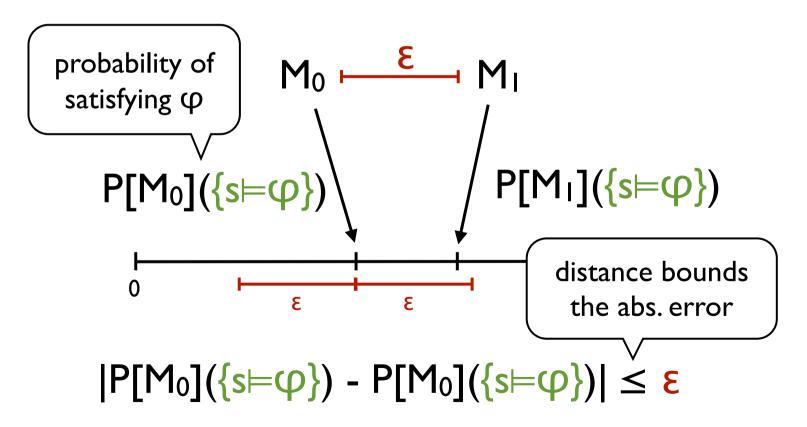
$$|P[M_0](\{s \models \phi\}) - P[M_0](\{s \models \phi\})|$$

Distance Approx. Error



$$|P[M_0](\{s \models \phi\}) - P[M_0](\{s \models \phi\})|$$

Distance [?] Approx. Error



Trace Distance vs. Model Checking

(i.e., does it provide a good approximation error?)

i.e., measuring the likelihood that a a linear real-time property is satisfied by the SMC

SMC ⊨ Linear Real-time Spec.

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represented as

Metric Temporal Logic
formulas

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... or languages recognized by <u>Timed Automata</u>

i.e., measuring the likelihood that a a linear real-time property is satisfied by the SMC

a proper measurable set!

SMC ⊨ Linear Real-time Spec.

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... or languages recognized by <u>Timed Automata</u>

(Alur-Henzinger)

Metric Temporal Logic

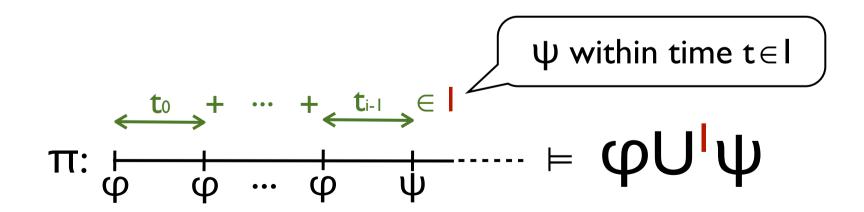
$$\phi \coloneqq p \mid \bot \mid \phi \rightarrow \phi \mid X^{'} \phi \mid \phi U^{'} \phi$$

(*) $I \subseteq \mathbb{R}$ closed interval with rational endpoints

(Alur-Henzinger)

Metric Temporal Logic

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MTL distance

(max error w.r.t. MTL properties)

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set of timed paths that satisfy
$$\phi$$
 measurable in $\sigma(\mathcal{T})$

$$MTL(s,s') = \sup_{\varphi \in MTL} |P[s](\{\pi \models \varphi\}) - P[s'](\{\pi \models \varphi\})|$$

Relation with Trace Distance

$$MTL(s,s') \le d(s,s') = \sup_{E \in \sigma(\mathcal{T})} |P[s](E) - P[s'](E)|$$

MTL distance

(max error w.r.t. MTL properties)

$$\begin{array}{c} \text{set of timed paths} \\ \text{that satisfy } \phi \end{array} \begin{array}{c} \text{measurable} \\ \text{in } \sigma(\mathcal{T}) \end{array}$$

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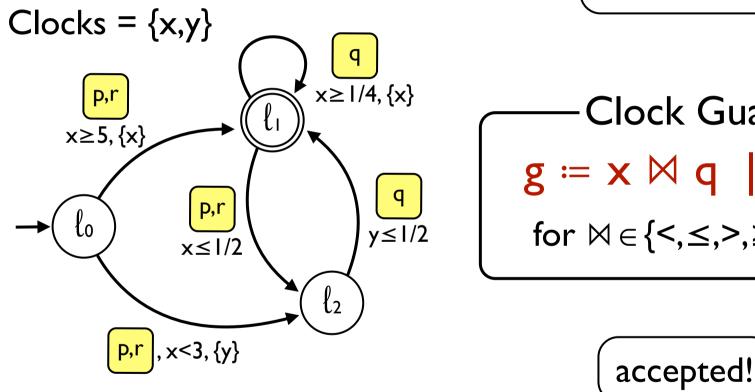
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(Alur-Dill)

(Muller) Timed Automata

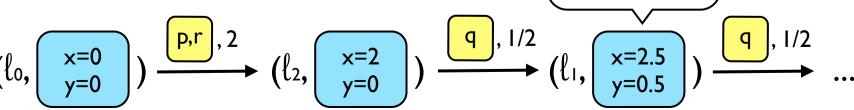
without invariants



Clock Guards-

$$g = x \bowtie q \mid g \wedge g$$

for $\bowtie \in \{<, \leq, >, \geq\}, q \in \mathbb{Q}$



TA distance

(max error w.r.t. timed regular properties)

set of timed paths accepted by \mathcal{A} TA(s,s') = sup $|P[s](\{\pi \in L(\mathcal{A})\}) - P[s'](\{\pi \in L(\mathcal{A})\})|$ $\mathcal{A} \in TA$

TA distance

(max error w.r.t. timed regular properties)

set of timed paths accepted by
$$\mathcal{A}$$
 measurable in $\sigma(\mathcal{T})$

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TA distance

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 $cA \in TA$

Relation with Trace Distance

$$TA(s,s') = d(s,s') = \sup_{E \in \sigma(\mathcal{T})} |P[s](E) - P[s'](E)|$$

The theorem behind...

For $\mu, \nu: \Sigma \to \mathbb{R}_+$ finite measures on (X, Σ) and $F\subseteq\Sigma$ field such that $\sigma(F)=\Sigma$

Representation Theorem
$$||\mu - \nu|| = \sup_{E \in F} |\mu(E) - \nu(E)|$$

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F is much simpler than Σ , nevertheless it suffices to attain the supremum!

$$MTL(s,s') = MTL^{\neg \cup}(s,s')$$

$$TA(s,s') = DTA(s,s') = I-DTA(s,s') = I-RDTA(s,s')$$

$$\max_{\text{without Until}} \text{max error w.r.t. } \phi \in \text{MTL}$$

$$\text{without Until}$$

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max error w.r.t.
Deterministic TAs

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max error w.r.t. φ∈MTL without Until

 $MTL(s,s') = MTL^{\neg \cup}(s,s')$

max error w.r.t.

Deterministic TAs

$$TA(s,s') = DTA(s,s') = I-DTA(s,s') = I-RDTA(s,s')$$

max error w.r.t. single-clock DTAs

max error w.r.t. φ∈MTL without Until

 $MTL(s,s') = MTL^{\cup}(s,s')$

max error w.r.t.

Deterministic TAs

max error w.r.t.
Resetting I-DTAs

$$TA(s,s') = DTA(s,s') = I-DTA(s,s') = I-RDTA(s,s')$$

max error w.r.t. single-clock DTAs

Computing the trace distance...

NP-hardness [Lyngsø-Pedersen JCSS'02]

Approximating the trace distance up to any \$\iiint \text{0}\$ whose size is polynomial in the size of the MC is NP-hard.

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reduction from the max-clique problem

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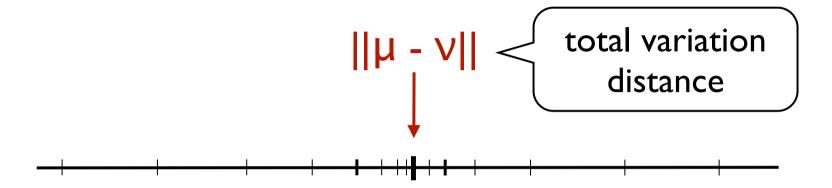
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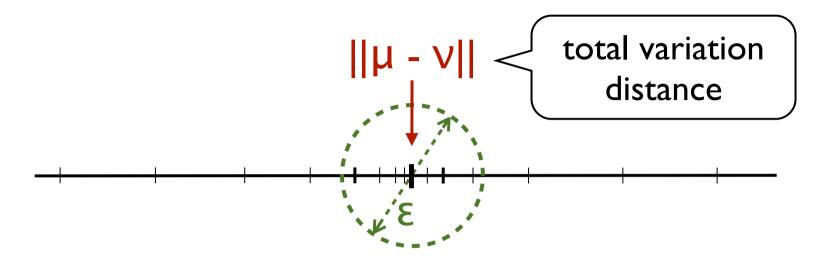
reduction from the max-clique problem

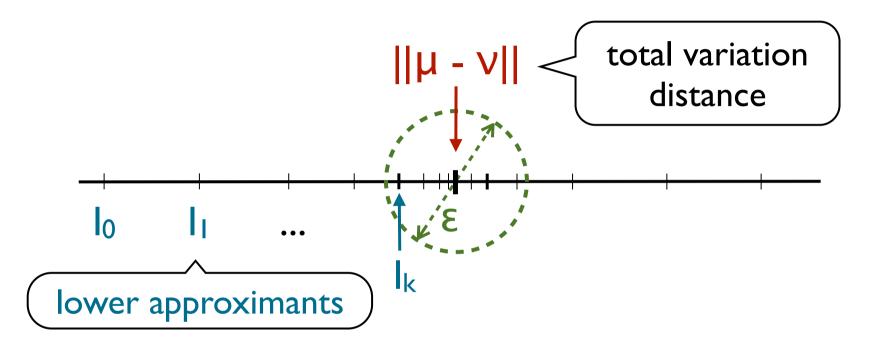
Decidability still an open problem!

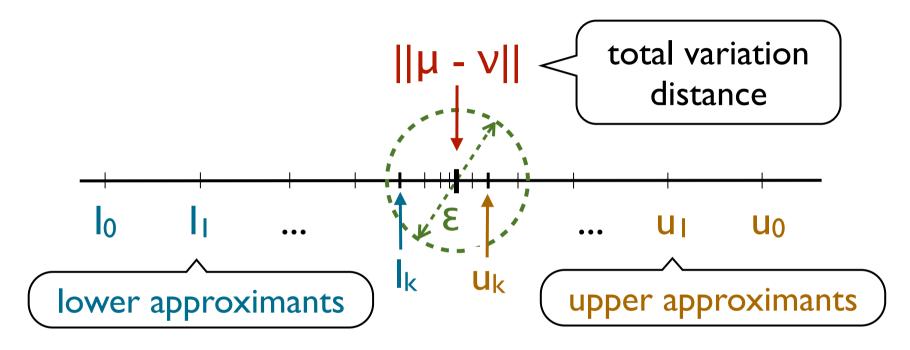
Approximation Algorithm for the Trace Distance

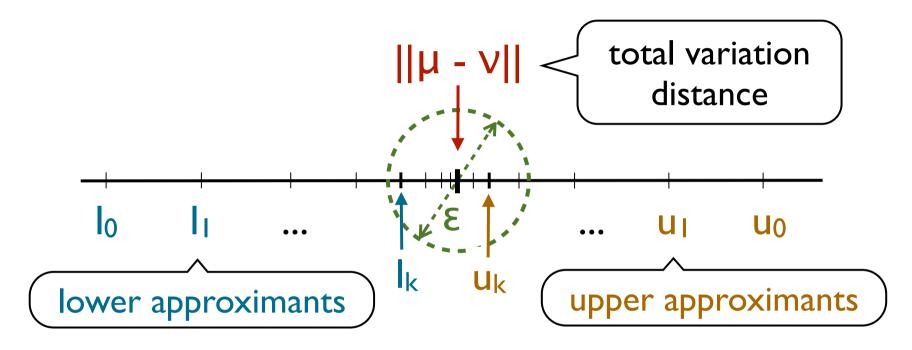
(from below & from above)



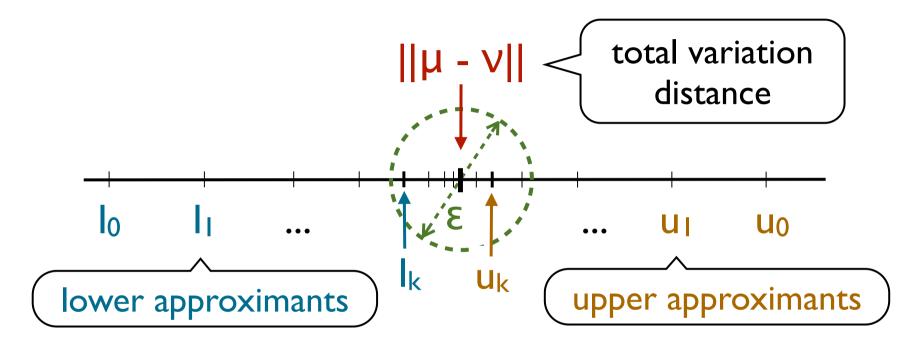








• I_i and u_i must converge to $||\mu - \nu||$,



- I_i and u_i must converge to $||\mu \nu||$,
- For all $i \in \mathbb{N}$, I_i and u_i must be computable.

Representation Theorem —
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F field that generates Σ

Representation Theorem — recall that...

$$||\mu - \nu|| = \sup_{E \in F} |\mu(E) - \nu(E)|$$

$$E \in F$$
F field that generates Σ

We need $F_0 \subseteq F_1 \subseteq F_2 \subseteq ...$ such that $U_i F_i = F$

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so that
$$\forall i \geq 0, |i| \leq |i| \leq$$

Approx. Trace Distance

from below

Provide $F_0 \subseteq F_1 \subseteq F_2 \subseteq ...$ such that U_i F_i is a field for $\sigma(\mathcal{T})$

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Take F_i to be the collection of finite unions of cylinders

$$\mathfrak{C}(L_0,R_0,...,R_{i-1},L_i)\in \mathcal{T}$$

where
$$R_j \in \{ \left[\frac{n}{2^i}, \frac{n+1}{2^i} \right) \mid 0 \le n \le i2^i \} \cup \{ \left[i, \infty \right) \}$$

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each repartitioned in 2ⁱ [closed-open) intervals

... from aboveCoupling Characterization

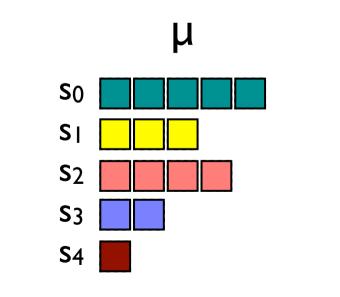
$$||\mu - \nu|| = \min \{w(\neq) \mid w \in \Omega(\mu, \nu)\}$$

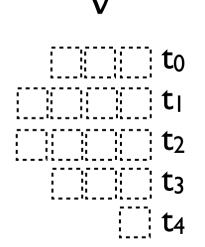
Coupling Characterization

it is know that.

$$||\mu - \nu|| = \min \{w(\neq) \mid w \in \Omega(\mu, \nu)\}$$

Coupling as a transportation schedule...



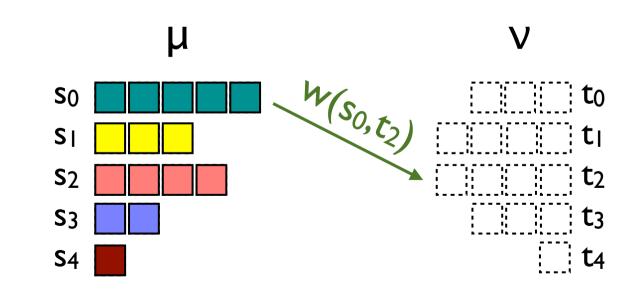


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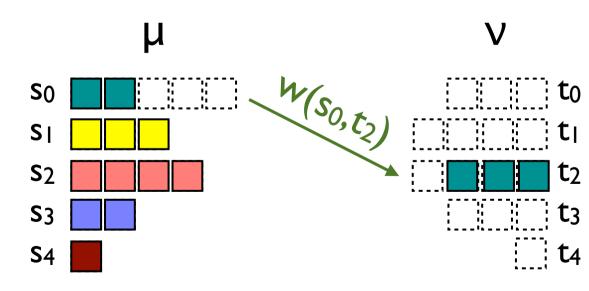


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... from aboveCoupling Characterization

$$||\mu - \nu|| = \min \{w(\neq) \mid w \in \Omega(\mu, \nu)\}$$

... from above _____ Coupling Characterization _____
$$\frac{it \ is \ know}{that...}$$
 | $\mu - \nu$ | = min $\{w(\not=) \mid w \in \Omega(\mu, \nu)\}$

We need $\Omega_0 \subseteq \Omega_1 \subseteq \Omega_2 \subseteq ...$ such that $U_i \Omega_i$ dense in $\Omega(\mu, \nu)$ w.r.t. total variation

$$u_i = \inf \{ w(\neq) \mid w \in \Omega_i \}$$

... from above

Coupling Characterization

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$$u_i = \inf \{ w(\neq) \mid w \in \Omega_i \}$$

so that
$$\forall i \geq 0, u_i \geq u_{i+1}$$
 & $\inf_i u_i = ||\mu - \nu||$ decreasing limiting

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coupling structure

of rank k

 $C: S \times S \rightarrow \Delta(\Pi^k S \times \Pi^k S)$

such that $C(s,s') \in \Omega(P[s]^k,P[s']^k)$

Stochastic process generating pairs of timed paths divided in multisteps of length k

Decidability

- Al: residence-time distributions are computable on [q,q') with $q,q' \in \mathbb{Q}_+$
- A2: total variation between residence-time distributions is computable

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Trace Distance vs Model Checking

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- General results for Total Variation distance:

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- General results for Total Variation distance:
 - algebraic representation theorem
 - approximation strategies
- Approx. algorithm for Trace Distance
- Relation with Kantorovich dist. (not shown)

Thank you for the attention